

L Number	Hits	Search Text	DB	Time stamp
4	31602	((timing\$2 separation\$2) near9 (circuit\$5 generat\$5 flip-flop\$2)) AND (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop")	USPAT	2004/04/14 09:54
5	1934	342/124,175,205.ccls. 73/290R, 290V.ccls.) (324/644.ccls. 73/304R,304c, 305-322, 322.5.ccls.)	USPAT	2004/04/14 09:57
6	201	324/644.ccls. 73/304R,304c, 305-322, 322.5.ccls.	USPAT	2004/04/14 09:55
7	34	((timing\$2 separation\$2) near9 (circuit\$5 generat\$5 flip-flop\$2)) AND (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop") and (342/124,175,205.ccls. 73/290R, 290V.ccls.) (324/644.ccls. 73/304R,304c, 305-322, 322.5.ccls.)	USPAT	2004/04/14 09:57
8	123	342/124.ccls.	USPAT	2004/04/14 10:59
9	679279	((time\$2 timing\$2 separation\$2) near9 (control\$2 generat\$5 detect\$5 sens\$5 difference\$5 chatter\$5)) (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop")	USPAT	2004/04/14 10:59
10	66197	((time\$2 timing\$2 separation\$2) near9 (control\$2 generat\$5 detect\$5 sens\$5 difference\$5 chatter\$5)) (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop") .ab.	USPAT	2004/04/14 10:58
11	787	((time\$2 timing\$2 separation\$2) near9 (control\$2 generat\$5 detect\$5 sens\$5 difference\$5 chatter\$5)) (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop") and (342/124,175,205.ccls. 73/290R, 290V.ccls.) (324/644.ccls. 73/304R,304c, 305-322, 322.5.ccls.)	USPAT	2004/04/14 10:59
12	84	((time\$2 timing\$2 separation\$2) near9 (control\$2 generat\$5 detect\$5 sens\$5 difference\$5 chatter\$5)) (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop") and 342/124.ccls.	USPAT	2004/04/14 10:59
13	142	((time\$2 timing\$2 separation\$2) near9 (control\$2 generat\$5 detect\$5 sens\$5 difference\$5 chatter\$5)) (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop") .ab.) and (342/124,175,205.ccls. 73/290R, 290V.ccls.) (324/644.ccls. 73/304R,304c, 305-322, 322.5.ccls.)	USPAT	2004/04/14 10:59
14	20	((time\$2 timing\$2 separation\$2) near9 (control\$2 generat\$5 detect\$5 sens\$5 difference\$5 chatter\$5)) (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop") .ab.) and 342/124.ccls.	USPAT	2004/04/14 10:59
15	82	((time\$2 timing\$2 separation\$2) near9 (control\$2 generat\$5 detect\$5 sens\$5 difference\$5 chatter\$5)) (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop") and (342/124,175,205.ccls. 73/290R, 290V.ccls.) (324/644.ccls. 73/304R,304c, 305-322, 322.5.ccls.) and (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop")	USPAT	2004/04/14 11:14
16	11	((time\$2 timing\$2 separation\$2) near9 (control\$2 generat\$5 detect\$5 sens\$5 difference\$5 chatter\$5)) (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop") and 342/124.ccls.) and (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop")	USPAT	2004/04/14 11:01
18	6	((time\$2 timing\$2 separation\$2) near9 (control\$2 generat\$5 detect\$5 sens\$5 difference\$5 chatter\$5)) (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop") .ab.) and 342/124.ccls.) and (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop")	USPAT	2004/04/14 11:06
17	27	((time\$2 timing\$2 separation\$2) near9 (control\$2 generat\$5 detect\$5 sens\$5 difference\$5 chatter\$5)) (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop") .ab.) and (342/124,175,205.ccls. 73/290R, 290V.ccls.) (324/644.ccls. 73/304R,304c, 305-322, 322.5.ccls.) and (flip-flop\$1 "D-flipflop" "D-flip-flop" "flipflop" "d flip flop")	USPAT	2004/04/14 11:01
19	208377	((transmit\$5 same receive\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))	USPAT	2004/04/14 11:09

20	59293	((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and ((sens\$5 detect\$5 level\$2 radar\$2 determin\$5) near\$ (level\$2 gaug\$5))	USPAT	2004/04/14 11:13
21	4946	((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and ((sens\$5 detect\$5 level\$2 radar\$2 determin\$5) near\$ (level\$2 gaug\$5)).ab.)	USPAT	2004/04/14 11:13
25	14	("4044353" "4737791" "4847623" "5563605" "5651286" "5659321" "5672975" "5701006" "5851083" "6072427" "6087978" "6107957" "6130637" "6137438").PN.	USPAT	2004/04/14 11:11
26	59293	((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and ((sens\$5 detect\$5 level\$2 radar\$2 determin\$5) near\$ (level\$2 gaug\$5)) and ((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2)))	USPAT	2004/04/14 11:13
27	4946	((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and ((sens\$5 detect\$5 level\$2 radar\$2 determin\$5) near\$ (level\$2 gaug\$5)).ab.) and ((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2)))	USPAT	2004/04/14 11:13
28	9583	((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and ((sens\$5 detect\$5 level\$2 radar\$2 determin\$5) near\$ (level\$2 gaug\$5)) and ((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and (flip-flop\$1 "D-flipflop"	USPAT	2004/04/14 11:14
29	629	((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and ((sens\$5 detect\$5 level\$2 radar\$2 determin\$5) near\$ (level\$2 gaug\$5)).ab.) and ((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and (flip-flop\$1 "D-flipflop"	USPAT	2004/04/14 11:14
30	17	((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and ((sens\$5 detect\$5 level\$2 radar\$2 determin\$5) near\$ (level\$2 gaug\$5)).ab.) and ((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and (flip-flop\$1 "D-flipflop"	USPAT	2004/04/14 11:34
31	27	((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and ((sens\$5 detect\$5 level\$2 radar\$2 determin\$5) near\$ (level\$2 gaug\$5)).ab.) and ((transm1\$5 same receiv\$5 same (separat\$5 control\$2 timing\$1 time\$2 chatter\$2))) and (flip-flop\$1 "D-flipflop"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/14 11:36
-	2	("6700530").PN.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 14:45
-	2	("6300897").PN.	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/13 15:32
-	1	6300897.URPN.	USPAT	2004/04/13 15:37
-	0	6628229.URPN.	USPAT	2004/04/13 15:31
-	1764	342/124,175,205.ccls. 73/290R, 290V.ccls.	USPAT	2004/04/13 15:41
-	1152	73/290R, 290V.ccls.	USPAT	2004/04/13 15:41
-	138813	((timing\$2 separation\$2) near\$ (circuit\$5 generat\$5 filp-flop\$2))	USPAT	2004/04/14 09:52

-	52	((timing\$2 separation\$2) near9 (circuit\$5 generat\$5 flip-flop\$2))) and	USPAT	2004/04/14 09:54
		(flip-flop\$2)		

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